

To Advance Wafer Test Technology

o To Serve and Inform the Wafer Test Professional

o To Boldly Go Where No Workshop Has Gone Before

Long Beach, CA, June 1 to 4, 2003



## WELCOME TO LONG BEACH



IEEE SWTW - 2003 June 1 to 4



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## **WHAT IS SWTW - 2003?**

- "THE" Conference for wafer test professionals
- Probe technology forum
- Not a theoretical or academic conference
- Provides practical solutions to real problems
- Mixture of vendor and user presentations
- Informal and relaxed atmosphere



## **INFORMAL CONFERENCE**

- Long breaks
- Plenty of networking opportunities
- Informal discussions
- Numerous social activities
- Meet new people & have some fun!

## (Don't tell the IEEE about the fun part)



SOCIAL ACTIVITIES

#### Monday after dinner *light exercise*

#### Probe Test Engineering Triathlon

- 1.5 Meter Cherry Seed Spitting
- 3 Meter Paper Airplane Toss for Accuracy
- 5 Meter Blindfolded Frisbee Throw

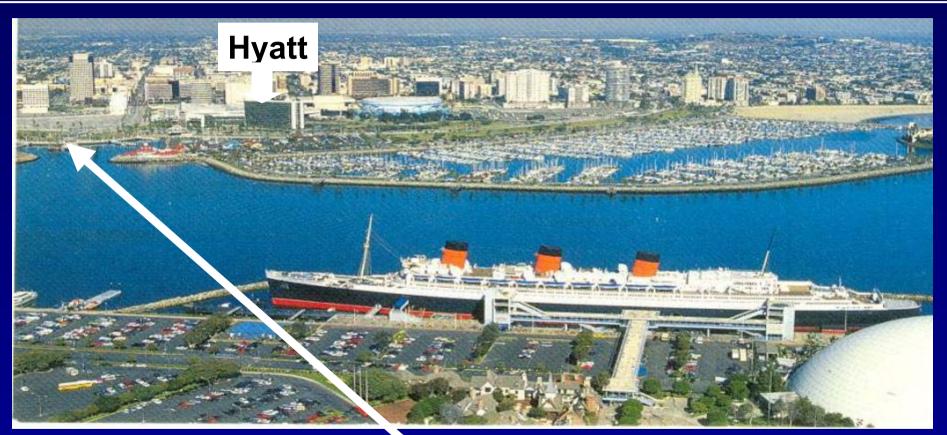
#### Team Event

- Three (3) individuals per team
- Must be from different companies
- All members participate in each event

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## SOCIAL ACTIVITIES

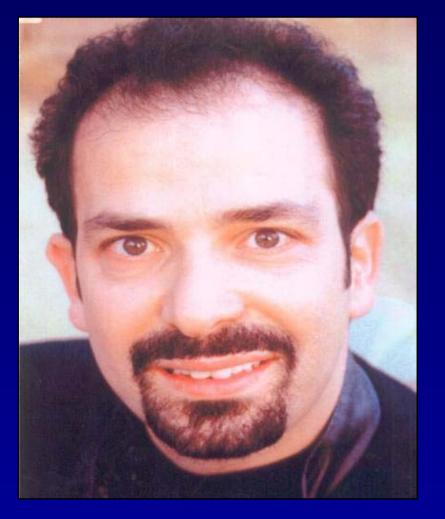


### Tuesday Afternoon Harbor Sightseeing Cruise

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## SOCIAL ACTIVITIES



#### Tuesday Evening

 Triathlon Awards Banquet

Comedian...
Nazareth
"American By Choice"

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## **SWTW – 2003 COMMITTEE**

#### Organization and Technical Program

- William Mann, SWTW General Chair
- Jerry Broz, Ph.D., Point Technologies, Technical Program Chair
- Maddie Harwood, CEM Inc, Registration and Finance Chair

#### • Technical Committee and Session Chairs

- Michael Egloff, AMD
- Tom Foerster, Jazz Semiconductor
- Gavin Gibson, Infineon Technologies
- Michael Harris, Texas Instruments
- Ken Karklin, Agilent Technologies
- Ger Koch, Philips Semiconductor

- Rey Rincon, Kulicke and Soffa
- Phil Seitzer, Agere Systems
- Roger Sinsheimer, Xandex
- Tim Swettlen, Intel
- Fred Taber, IBM Microelectronics
- Bill Williams, Motorola



## **TECHNICAL PROGRAM**

#### • Sunday, June 1, 2003

- Tutorial: The Impact of Design For Test on the Cost of Test
- Keynote Speaker Brian Matas (VP of IC Insights)

#### "The IC Market Recovery Outlook"

#### • Monday, June 2, 2003

- New Probe Technologies Potpourri
- Advances in Memory Probing
- Vertical Probe Technologies
- Metal Stack and Dielectric Characterization
- Cocktail Reception & Dinner
- Probe Test Engineering Triathlon

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## **TECHNICAL PROGRAM**

#### • Tuesday, June 3, 2003

- MEMs Technologies
- Controlling Contact Resistance
- Afternoon Social Activities
  - Long Beach Harbor Sight Seeing Cruise
- Cocktail Reception
- Dinner and Comedy Entertainment

#### • Wednesday June 4, 2003

- Probe Process Characterization and Improvement
- Advances in Probe Card Analyzers
- Best Presentation Awards

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## **RECOGNITION & AWARDS**

- Best Overall Presentation
- Best Data Presented
- Best Presentation, Tutorial in Nature
- Most "Inspirational" Presentation
- Engineering Triathlon Winners
- Other "Special Awards"



Brett Grossman and Tim Swettlen, Intel

"Modeling Distributed Power Delivery Effects in High Performance Sort Interface Units"

Sam McKnight, <u>IBM Microelectronics</u>

"Probing Lead Free Solder Bumps in Final Wafer Test"

• William Knauer, <u>Keithley Instruments, Inc.</u>

"RF S-Parameter Measurements - A Production Solution"

#### • Rainer Gaggl, Ph.D., <u>T.I.P.S. Messtechnik GmbH</u>

"Probing 10 kV and 100 Amps: Challenges and Solutions for High Voltage / High Current Wafer Probing"

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## http://www.swtest.org

#### Central Online Repository

- Past presentations
- Online registration
- With more features to come......

#### • Tremendous continued success!!

- Over eight thousand visits to the site last year
- Thanks to "web-efforts" of Jerry Broz



We think of everything, almost...

## Souvenirs and a "Post Card Home"

## "You get to go to Long Beach and have a lot of fun.....

# ..... and all I get is this crummy toy!"

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